


<b>Search Notes</b>  	<b>Application/Control No.</b>  10534108	<b>Applicant(s)/Patent Under Reexamination</b>  FAYE ET AL.
	<b>Examiner</b>  McGraw, Trevor	<b>Art Unit</b>  3752

SEARCHED			
Class	Subclass	Date	Examiner
239	567,461,463,492,482,483,398,399	01/04/2006	TEM

SEARCH NOTES		
Search Notes	Date	Examiner
East and text search, See attached East History, Search provided by: Davis Hwu	01/04/2006	TEM
laser with weld, metering with chamber, 1 and 2	07/09/2007	TEM
metering with chamber, reduced, wall, thickness; 1 and 60/\$.ccls., 1 and 48/\$.ccls., 1 and 239/\$.ccls.	01/05/2008	TEM
Examiner updated search based on new interpretation of the present claims and better understanding of chemical reformer language.	9/9/2010	TEM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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